EC 4210 Solutions

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Assignment 5

- 16.4. Consider a silicon photoconductor with the dimensions as shown in Fig. 6.5 irradiated by light. The index of refraction of the material is 1.5.
- a. Calculate the fraction of the incident power that will be absorbed by the device at 800 nm. . . . at 1 μ m?
- b. Using Fig. 17.6 on page 262 of these notes, calculate the device transit time for a voltage value of 400 volts at $T = 298 \, \text{K}$.
- c. Suppose that the carrier lifetime is 20 ns. Calculate the output current that would be expected for a 400 volt bias when irradiated by 1 pW of laser light at 632.8 nm. The quantum efficiency of the device at the wavelength of interest is assumed to be 60%.
- d. Find the normalized mean-square noise current (in units of A^2/Hz^{-1}) associated with the generation-recombination noise for a direct detection test signal at 100 MHz.
- e. Calculate the mean-square signal current for $P_s=1\,$ pW with $m=1\,$.
- f. Calculate the resulting signal-to-noise ratio in dB if the noise bandwidth is 10 MHz.
- g. Calculate the minimum detectable power for direct detection with this detector if $B=10~\mathrm{MHz}$.
- h. Calculate the minimum detectable power for heterodyne detection with this detector.

Solution: a. We need the reflection coefficient.

$$R = \left(\frac{n-1}{n+1}\right)^2 = \left(\frac{1.5-1}{1.5+1}\right)^2 = \left(\frac{0.5}{2.5}\right)^2 = 0.04.$$
 (1)

We know from our previous work that

$$\frac{P(w)}{P_{\text{inc}}} = (1 - R)e^{-\alpha d}(1 - e^{-\alpha w}).$$
 (2a)

We have d=0, R=0.04 and $w=5\times 10^{-3}$. For $\lambda=800$ nm, we estimate our absorption coefficient from Fig. 16.2 on page 247 as $\alpha=2\times 10^5$ m⁻¹, so

$$\frac{P(w)}{P_{\text{inc}}} = 0.96(1)(1 - e^{-(2 \times 10^5)(5 \times 10^{-3})}) = 0.96.$$
 (2b)

So, 96% of the power that is not reflected is absorbed.

For $\lambda = 1 \times 10^{-6}$, we estimate our absorption coefficient from Figure 16.2 as $\alpha = 1.8 \times 10^4 \text{ m}^{-1}$, **Revised** 3/2/99

so

$$\frac{P(w)}{P_{\text{inc}}} = 0.96(1)(1 - e^{-(1.8 \times 10^4)(5 \times 10^{-3})}) = 0.96.$$
 (2c)

The slightly decreased absorption coefficient did not change the fraction of light absorbed.

b. We know that E = V/l. At 400 volts, we have

$$E = \frac{V}{l} = \frac{400}{1} = 400 \text{ V} \cdot \text{cm}^{-1}.$$
 (3)

From the carrier velocity curve (Fig. 17.6 on page 262), we find that that the velocity of the holes is about 2×10^5 cm/s (= 2×10^3 m/s) and that of electrons is about 6.5×10^5 cm/s (= 6.5×10^3 m/s). From this data, we calculate the average speed of a carrier as

$$\langle v \rangle = \frac{2 \times 10^3 + 6.5 \times 10^3}{2} = 4.25 \times 10^3 \text{ m} \cdot \text{s}^{-1}.$$
 (4)

The transit time τ_d is

$$\tau_d = \frac{l}{\langle v \rangle} = \frac{1 \times 10^{-2}}{4.25 \times 10^3} = 2.35 \times 10^{-6} \text{ s} = 2.35 \ \mu\text{s}. \tag{5}$$

c. Let V=400 and we know that $\tau_0=20\times 10^{-9}$ s. We irradiate with 1×10^{-6} at $\lambda=632.8\times 10^{-9}$ with a quantum efficiency of $\eta=0.60$. The absorbed power is

$$P_{\rm abs} = 0.96 P_{\rm inc} = 0.96 \times 10^{-12}$$
 W (6)

from part a. The dc current, then, is

$$\overline{i} = \frac{Pq\eta\lambda}{hc} \frac{\tau_0}{\tau_d}
= \left(\frac{(0.96 \times 10^{-12})(1.6 \times 10^{-19})(0.60)(632.8 \times 10^{-9})}{(6.63 \times 10^{-34})(3.0 \times 10^8)}\right) \left(\frac{(20 \times 10^{-9})}{(2.35 \times 10^{-6})}\right) = 2.49 \times 10^{-15} \text{ A}.$$

d. The signal frequency is $\omega_s = 2\pi (1 \times 10^8) = 6.28 \times 10^8$ Hz. The normalized mean-square noise current associated with the generation–recombination noise is

$$\frac{\langle i_N^2 \rangle}{B} = \frac{4\overline{i}q\left(\frac{\tau_0}{\tau_d}\right)}{1 + \omega_s^2 \tau_0^2} = \frac{4(2.49 \times 10^{-15})(1.6 \times 10^{-19})\left(\frac{20 \times 10^{-9}}{2.35 \times 10^{-6}}\right)}{1 + (6.28 \times 10^8)^2 (20 \times 10^{-9})^2}$$

$$= 8.52 \times 10^{-38} \text{A}^2 \cdot \text{Hz}^{-1}.$$
(8)

e. We want to find the mean-square signal current when $P = 1 \times 10^{-12}$ W. We first need to find the power absorbed by including the reflection loss.

$$P_{\text{abs}} = 0.96 P_{\text{inc}} = 0.96 \times 10^{-12} \text{ W}.$$
 (9)

$$\langle i_s^2 \rangle = \left(\frac{Pq\eta\lambda}{hc}\right)^2 \left(\frac{\tau_0}{\tau_s}\right)^2 \left(\frac{2m^2}{1+\omega_s^2\tau_0^2}\right)$$

$$= \left(\frac{(0.96 \times 10^{-12})(1.6 \times 10^{-19})(0.60)(632.8 \times 10^{-9})}{(6.63 \times 10^{-34})(3.0 \times 10^8)}\right)^2 \left(\frac{20 \times 10^{-9}}{2.35 \times 10^{-6}}\right)^2$$

$$\times \left(\frac{2(1)^2}{1+(2\pi \times 1 \times 10^8 \times 20 \times 10^{-9})^2}\right)$$

$$= 7.88 \times 10^{-32} \text{ A}^2 .$$

$$(10)$$

f. For $B = 1 \times 10^7$ Hz, we have

$$\frac{S}{N} = \frac{\langle i_s^2 \rangle}{\frac{\langle i_s^2 \rangle}{B}} = \frac{7.88 \times 10^{-32}}{(8.54 \times 10^{-38})(1 \times 10^7)} = 0.0923 \Rightarrow -10.35 \text{ dB}.$$
 (11)

Not very detectable!!

g. The minimum detectable power for direct detection with a photoconductor is

$$P_{\text{s min}} = \frac{3hcB}{\eta\lambda} = \frac{(3)(6.63 \times 10^{-34})(3.0 \times 10^8)(1 \times 10^7)}{(0.60)(632.8 \times 10^{-9})}$$

$$= 1.570 \times 10^{-11} \text{ W} = 15.70 \text{ pW}.$$
(12)

h. The minimum detectable power for heterodyne detection with a photoconductor is

$$P_{\min} = \frac{2hcB}{\eta \lambda_L} = \frac{(2)(6.63 \times 10^{-34})(3.0 \times 10^8)(1 \times 10^7)}{(0.60)(632.8 \times 10^{-9})}$$

$$= 1.049 \times 10^{-11} \text{ W} = 10.49 \text{ pW}.$$
(13)

16.5 Find the minimum detectable power that a detector with a quantum efficiency of 1 will have when used in heterodyne detection with a 500 nm source and a 1 Hz nominal bandwidth.

Solution: The minimum detectable power for heterodyne detection with a photoconductor is given by Eq. 16.23 as

$$P_{\rm s min} = \frac{2hcB}{\eta \lambda_L} = \frac{(2)(6.63 \times 10^{-34})(3.0 \times 10^8)}{(1)(500 \times 10^{-9})} = 7.97 \times 10^{-19} \text{ W}.$$
 (14)

- 17.1. Consider a silicon photodiode with uniform acceptor doping concentration of 1×10^{21} atoms/m³ and a uniform donor doping of 5×10^{21} atoms/m³.
- a. Calculate V_d if $n_i=1.8\times 10^{16}$ atoms/m³ at room temperature. (Note: kT/q=0.0259 volts at room temperature (300K).)
- b. Calculate l_p , l_n , and w for 0 volts of reverse bias.
- c For 10 volts of reverse bias?

- d For 100 volts of reverse bias?
- e. Find the value of the maximum electric field inside the crystal for 10 volts of reverse bias.
- f. Find the device capacitance at 10 volts reverse bias if the circular detector's diameter is 1 mm.

Solution: a. Given that $n_i = 1.8 \times 10^{16}$ and kT/Q = 0.0259 volts at room temperature, we find V_d as

$$V_d = \frac{kT}{q} \ln \left(\frac{N_D N_A}{n_i^2} \right) = 0.0259 \ln \left(\frac{(1 \times 10^{21})(5 \times 10^{21})}{(1.8 \times 10^{16})^2} \right) = 0.608 \text{ volts}.$$
 (15)

b. For $V_a = 0$ volts we find

$$l_n = \left(\sqrt{V_a + V_d}\right) \left(\sqrt{\frac{2\epsilon}{q}}\right) \left(\sqrt{\frac{N_A}{N_D(N_A + N_D)}}\right)$$

$$= \left(\sqrt{0 + 0.608}\right) \left(\sqrt{\frac{2(1.044 \times 10^{-12})}{1.6 \times 10^{-19}}}\right) \left(\sqrt{\frac{1 \times 10^{21}}{(5 \times 10^{21})(6 \times 10^{21})}}\right)$$

$$= 1.626 \times 10^{-8} \text{ m} = 16.26 \text{ nm},$$
(16a)

and

$$l_p = \left(\sqrt{V_a + V_d}\right) \left(\sqrt{\frac{2\epsilon}{q}}\right) \left(\sqrt{\frac{N_D}{N_A(N_A + N_D)}}\right)$$

$$= \left(\sqrt{0 + 0.608}\right) \left(\sqrt{\frac{2(1.044 \times 10^{-12})}{1.6 \times 10^{-19}}}\right) \left(\sqrt{\frac{5 \times 10^{21}}{(1 \times 10^{21})(6 \times 10^{21})}}\right)$$

$$= 8.13 \times 10^{-8} \text{ m} = 81.3 \text{ nm}.$$
(16b)

Adding the two depletion lengths, we find

$$w = l_n + l_n = 16.26 + 81.3 = 97.5 \text{ nm}.$$
 (16c)

c. For $V_a = 10$ volts, we find

$$l_n(10 \text{ volts}) = l_n(0 \text{ volts}) \sqrt{\frac{V_a + V_d}{V_d}} = 16.26 \sqrt{\frac{10.61}{0.608}} = 67.9 \text{ nm}$$
 (17a)

and

$$l_p(10 \text{ volts}) = l_p(0 \text{ volts}) \sqrt{\frac{V_a + V_d}{V_d}} = 81.3 \sqrt{\frac{10.61}{0.608}} = 339 \text{ nm}.$$
 (17b)

Adding the two depletion lengths, we find

$$w = l_n + l_p = 67.9 + 339 = 408 \text{ nm}.$$
 (17c)

d. For $V_a = 100$ volts we find

$$l_n(100 \text{ volts}) = l_n(0 \text{ volts}) \sqrt{\frac{V_a + V_d}{V_d}} = 16.26 \sqrt{\frac{100.6}{0.608}} = 209 \text{ nm},$$
 (18a)

and

$$l_p(100 \text{ volts}) = l_p(0 \text{ volts}) \sqrt{\frac{V_a + V_d}{V_a}} = 81.3 \sqrt{\frac{100.6}{0.608}} = 1045 \text{ nm}.$$
 (18b)

Adding the two depletion lengths, we find

$$w = l_n + l_p = 209 + 1045 \text{ nm} = 1.255 \ \mu\text{m}.$$
 (18c)

e. The value of E_{max} for $V_a = 10$ volts is

$$E_{\text{max}} = \frac{2(V_d + V_a)}{w} = \frac{2(10.61)}{406 \times 10^{-9}} = 52.1 \times 10^6 \text{ V} \cdot \text{m}^{-1}.$$
 (19)

f. The device capacitance is

$$C_d = \frac{\epsilon A}{w} = \frac{(1.044 \times 10^{-12})(\frac{\pi}{4})(1 \times 10^{-3})^2}{408 \times 10^{-9}} = 2.01 \times 10^{-9} = 2.01 \text{ pF}.$$
 (20)

17.2. Consider a silicon photodiode with a depletion layer that begins 5 μ m below the top surface of the detector. Using the results of Problem 2 on Photoconductors, calculate the fraction of the incident light that will be absorbed in the depletion layer (at $\lambda=0.6\mu$ m) for ...

a ... a pn junction that is 1 μ m thick (i.e., $w=1\mu$ m).

b. . . . a pin junction that is 5 μ m thick

Solution: We know that

$$\frac{P(w)}{P_{\text{inc}}} = (1 - R) \left(e^{-\alpha d} \right) \left(1 - e^{-\alpha w} \right) \tag{21a}$$

and that

$$R = \left(\frac{n_1 - n_2}{n_1 + n_2}\right)^2 = \left(\frac{1.5 - 1}{1.5 + 1}\right)^2 = 0.04,$$
(21b)

so

$$1 - R = 0.96$$
. (21c)

a. From Fig. 16.2 on p. 249, we estimate the absorption coefficient for slicon at $\lambda = 0.6 \times 10^{-6}$ Revised. as $\alpha = 8.0 \times 10^5$ m⁻¹. For $w = 1 \times 10^{-6}$ m, we find 2/25/99

$$\frac{P(w)}{P_{\text{inc}}} = (0.96)(e^{-(8\times10^5)(5\times10^{-6})})\left(1 - e^{-(8\times10^5)(1\times10^{-6})}\right) = 0.00968 \Rightarrow 0.968\%$$
 (22a)

b. For $w = 5 \times 10^{-6}$, we find

$$\frac{P(w)}{P_{\text{inc}}} = (0.96)(e^{-(8\times10^5)(5\times10^{-6})})\left(1 - e^{-(8\times10^5)(5\times10^{-6})}\right) = 0.01758 \Rightarrow 1.758\%.$$
 (22b)

The increased depletion layer results in almost twice as much light being absorbed.

- 17.3. It is desired to operate a silicon photodiode in direct detect at a maximum frequency of 100 MHz with a 50Ω load resistance.
- a. Calculate A/w for the diode to meet this specification.
- b. Calculate the maximum transit time allowed for this device. Assuming that the carriers reach scattering-limited velocities of 6×10^6 cm/s, calculate the maximum width of the depletion layer.
- c. Using the results of parts a and b, calculate the maximum diameter that a circular diode can have and still meet the frequency specifications.

<u>Solution</u>: a. The maximum frequency is given by $f_{\text{max}} = 1/2\pi R_L C_d$ and the allowed device capacitance is $C_d = 1/2\pi R_L f_{\text{max}} = \epsilon A/w$, so

$$\frac{A}{w} = \frac{1}{2\pi R_L f_{\text{max}} \epsilon} = \frac{1}{2\pi (50)(1 \times 10^8)(1.044 \times 10^{-12})} = 30.5 \text{ m}.$$
 (23)

b. The carriers move with an average scattering-limited velocity of $\langle v \rangle = 6 \times 10^4 \text{ m} \cdot \text{s}^{-1}$, then $\omega_{\text{max}} \tau_d \ll 1 = 0.1$ and $\tau_d = w/\langle v \rangle = 0.1/\omega_{\text{max}}$. The width w is found from

$$w = \frac{0.1 < v >}{\omega_{\text{max}}} = \frac{(0.1)(6 \times 10^4)}{2\pi (1 \times 10^8)} = 9.55 \times 10^{-6} = 9.55 \ \mu\text{m}.$$
 (24)

c. We want to find the the maximum diameter D of a circular photodiode, using the results of parts a and b. We know that A/w = 30.5 with $w = 9.55 \times 10^{-6}$, so

$$A = 30.5w = (30.5)(9.55 \times 10^{-6}) = 2.91 \times 10^{-4}$$
. (25a)

Since $A = \pi D^2/4$, we have

$$D = \sqrt{\frac{4A}{\pi}} = \sqrt{\frac{(4)(2.91 \times 10^{-4})}{\pi}} = 1.926 \times 10^{-2} = 1.926 \text{ cm}.$$
 (25b)